X-Ray Spectrometry: Recent Technological Advances
Kouichi Tsuji (Editor), Jasna Injuk (Editor), René Van Grieken (Editor)


DESCRIPTION
X-Ray Spectrometry: Recent Technological Advances covers the latest developments and areas of research in the methodological and instrumental aspects of x-ray spectrometry.

* Includes the most advanced and high-tech aspects of the chemical analysis techniques based on x-rays

* Introduces new types of X-ray optics and X-ray detectors, covering history, principles, characteristics and future trends

* Written by internationally recognized scientists, all of whom are eminent specialists in each of the sub-fields

* Sections include: X-Ray Sources, X-Ray Optics, X-Ray Detectors, Special Configurations, New Computerization Methods, New Applications

This valuable book will assist all analytical chemists and other users of x-ray spectrometry to fully exploit the capabilities of this set of powerful analytical tools and to further expand applications in such fields as material and environmental sciences, medicine, toxicology, forensics, archaeometry and many others.

ABOUT THE AUTHOR
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